Applicant(s)/Patent Under Application/Control No. Reexamination 10/067,304 FUJII ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2179 Ba Huynh **U.S. PATENT DOCUMENTS** Date **Document Number** Name Classification Country Code-Number-Kind Code MM-YYYY US-2001/0023430 09-2001 SRINIVASAN, THIRU 709/204 Α US-6,772,393 08-2004 715/512 В Estrada et al. US-С D US-US-Е F US-US-G US-Н US-1 US-J US-Κ US-L US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U ٧

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